


<b>Search Notes</b> 	<b>Application/Control No.</b> 10541940	<b>Applicant(s)/Patent Under Reexamination</b> LEE ET AL.
	<b>Examiner</b> Guadalupe McCall, Yaritza	<b>Art Unit</b> 2859

SEARCHED			
Class	Subclass	Date	Examiner
33	755, 758, 768	12/29/2006	YGM

SEARCH NOTES		
Search Notes	Date	Examiner
33 / 755, 758, 768	12/29/2006	YGM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner